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1 An improved technique in porosity prediction: a neural network approach

Wong, P.M.; Gedeon, T.D.; Taggart, I.J.;
Geoscience and Remote Sensing, IEEE Transactions on , Volume: 33 , Issue: 4 , July 1995
Pages:971 - 980

[\[Abstract\]](#) [\[PDF Full-Text \(824 KB\)\]](#) **IEEE JNL**

2 The quantity analysis method research of oil and gas geo-anomaly information mining

Li Qing; Liu Suhong; Zhao Xiang; Wang Peijuan;
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Proceedings. 2003 IEEE International , Volume: 6 , 21-25 July 2003
Pages:3674 - 3678 vol.6

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3 Terrain following control of an unmanned underwater vehicle using artificial neural networks

Waldock, M.I.; Roberts, G.N.; Sutton, R.;
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